AZTEKE: Application specific test methodology for highly complex systems in automotive and communication applications

The goal of this project is to increase the design reliability and efficiency of application-specific integrated circuits to assure and improve the competitiveness of the German microelectronics industry. To ensure the reduction of "time to volume", new methodologies and tools for test preparation and design for testability (DFT) are becoming more important to handle the system complexity of future applications. Acquiring qualified and standardized test solutions for modular test of highly complex SoCs is the scope of the project. This will include the development of diagnosis capabilities and fault localization methodologies under timing and performance conditions allowing the test at high frequencies.

Project coordination:

Infineon Technologies AG
Dr.-Ing. Sebastian Sattler
fon:

Project partners:

- Atmel Germany GmbH
- Infineon Technologies AG
- NXP Semiconductors Germany GmbH

Funding initial:

BMBF F&E 01M3063

Runtime:

Fri, 01 March 2002 - Mon, 28 February 2005

Website:

Project Information

Final Report
Project Flyer (DE)
NL 01 2006 (PSB)
NL 01 2005 (PN)
NL 02 2004 (PB)
NL 01 2004 (PN)
NL 03 2003 (PN)
NL 02 2003 (PN)

Used Abbreviations

Abbreviation	Meaning
PR	Project Report
SPR	Short Project Report
PN	Project News
FPR	Final Project Report